

**Search Notes**

Application/Control No.

10/777,922

Examiner

Tri T. Ton

Applicant(s)/Patent under  
Reexamination

YANG ET AL.

Art Unit

2877

**SEARCHED**


Class	Subclass	Date	Examiner
356	237.3	3/10/2006	TT
356	237.2	3/14/2006	TT
356	237.4	3/14/2006	TT
356	237.5	3/14/2006	TT
356	239.1	3/14/2006	TT
356	239.3	3/14/2006	TT
250	559.4	3/14/2006	TT
250	559.41	3/14/2006	TT
250	559.42	3/14/2006	TT
250	559.45	3/14/2006	TT
356	237.1	6/1/2006	TT

**INTERFERENCE SEARCHED**


Class	Subclass	Date	Examiner
356	237.100	6/1/2006	TT

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
6215551 and 5179422 citation	3/15/2006	TT
inventers' name and company's name	3/15/2006	TT
key word	3/10/2006	TT
consulting with PE Hoa Pham	3/15/2006	TT
IEEE Xplore	6/1/2006	TT


<b>Search Notes</b>  	Application/Control No.  10777922	Applicant(s)/Patent Under Reexamination  YANG ET AL.
	Examiner Ton, Tri T	Art Unit 2877

Notes	Date	Examiner
IEEE Xplore	06/01/2006	tt
U.S. Patent and Trademark Office		Part of Paper No.: 06022006

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	Examiner Ton, Tri T	Art Unit 2877

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356	237.100	06/01/2006	tt

U.S. Patent and Trademark Office	Part of Paper No.:	06022006
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	<p>Examiner</p> <p>Ton, Tri T</p>	<p>Art Unit</p> <p>2877</p>

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356	237.1	06/01/2006	tt

U.S. Patent and Trademark Office	Part of Paper No.: 06022006
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